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 Package Options Include Plastic Small-Outline (D) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) 300-mil DIPs

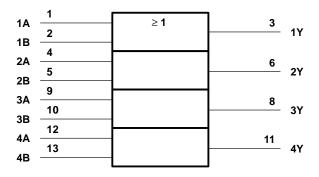
description

These devices contain four independent 2-input positive-OR <u>gates</u>. They perform the Boolean functions $Y = \overline{A} \cdot \overline{B}$ or Y = A + B in positive logic.

The SN54ALS32 and SN54AS32 are characterized for operation over the full military temperature range of -55° C to 125° C. The SN74ALS32 and SN74AS32 are characterized for operation from 0°C to 70°C.

FUNCTION TABLE (each gate)						
INP	UTS	S OUTPUT				
Α	В	Y				
Н	Х	Н				
Х	Н	н				
L	L	L				

logic symbol[†]



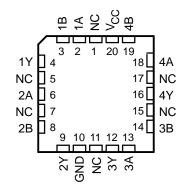
[†] This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

Pin numbers shown are for the D, J, and N packages.



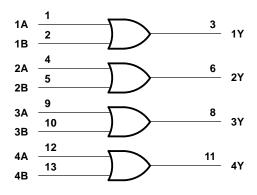
		$\overline{\mathbf{U}}$	
1A		U 14] V _{CC}] 4B
1B	2		
1Y	3	12	4A
2A	4	11] 4Y
2B		10] 3B
2Y	6	9] 3A
GND	7	8] 3Y

SN54ALS32, SN54AS32 . . . FK PACKAGE (TOP VIEW)



NC - No internal connection

logic diagram (positive logic)



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage, V _{CC}	
Operating free-air temperature range, T _A : SN54ALS32	
SN74ALS32	0°C to 70°C
Storage temperature range	-65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN54ALS32		SN	UNIT			
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
V _{CC}	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.8			0.8	V
ЮН	High-level output current			-0.4			-0.4	mA
IOL	Low-level output current			4			8	mA
TA	Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TERTO		SI	SN54ALS32		SN74ALS32			UNIT
PARAMETER	TESTC	TEST CONDITIONS		TYP‡	MAX	MIN	TYP‡	MAX	UNIT
VIK	V _{CC} = 4.5 V,	I _I = -18 mA			-1.5			-1.5	V
VOH	V_{CC} = 4.5 V to 5.5 V,	I _{OH} = -0.4 mA	V _{CC} –2	2		V _{CC} -2	2		V
Ve	V _{CC} = 4.5 V	$I_{OL} = 4 \text{ mA}$		0.25	0.4		0.25	0.4	V
VOL	VCC = 4.5 V	I _{OL} = 8 mA					0.35	0.5	v
Ц	V _{CC} = 5.5 V,	V _I = 7 V			0.1			0.1	mA
ЧН	V _{CC} = 5.5 V,	V _I = 2.7 V			20			20	μA
١ _{١L}	V _{CC} = 5.5 V,	V _I = 0.4 V			-0.1			-0.1	mA
١ _O §	V _{CC} = 5.5 V,	V _O = 2.25 V	-20		-112	-30		-112	mA
Іссн	V _{CC} = 5.5 V,	V _I = 4.5 V		1.9	4		1.9	4	mA
ICCL	V _{CC} = 5.5 V,	V _I = 0		2.6	4.9		2.6	4.9	mA

[‡] All typical values are at $V_{CC} = 5 V$, $T_A = 25^{\circ}C$.

\$ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	то (OUTPUT)	C _L = 50 pF, R _L = 500 Ω, T _A = MIN to		RL = 500 Ω, T _A = MIN to MAX¶		UNIT
			SN54A	LS32	SN74A	LS32	
			MIN	MAX	MIN	MAX	
^t PLH	A or B	V	3	18	3	14	ns
^t PHL	AUB		3	16	3	12	115

 \P For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



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absolute maximum ratings over operating free-air temperature range (unless otherwise noted)[†]

Supply voltage, V _{CC} Input voltage, V _I	
Operating free-air temperature range, T _A : SN54AS32	–55°C to 125°C
SN74AS32	0°C to 70°C
Storage temperature range	−65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

recommended operating conditions

		SN54AS32		S	UNIT			
		MIN	NOM	MAX	MIN	NOM	MAX	UNIT
Vcc	Supply voltage	4.5	5	5.5	4.5	5	5.5	V
VIH	High-level input voltage	2			2			V
VIL	Low-level input voltage			0.8			0.8	V
IOH	High-level output current			-2			-2	mA
IOL	Low-level output current			20			20	mA
TA	Operating free-air temperature	-55		125	0		70	°C

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

	TEST		SI	SN54AS32		SN74AS32			UNIT
PARAMETER	TESTC	TEST CONDITIONS		түр‡	MAX	MIN	typ‡	MAX	UNIT
VIK	V _{CC} = 4.5 V,	lı = –18 mA			-1.2			-1.2	V
VOH	V_{CC} = 4.5 V to 5.5 V,	$I_{OH} = -2 \text{ mA}$	V _{CC} -2			V _{CC} -2	2		V
VOL	$V_{CC} = 4.5 V,$	I _{OL} = 20 mA		0.35	0.5		0.35	0.5	V
l	$V_{CC} = 5.5 V,$	V _I = 7 V			0.1			0.1	mA
ЧΗ	$V_{CC} = 5.5 V,$	V _I = 2.7 V			20			20	μΑ
۱ _{IL}	V _{CC} = 5.5 V,	VI = 0.4 V			-0.5			-0.5	mA
١O§	V _{CC} = 5.5 V,	V _O = 2.25 V	-30		-112	-30		-112	mA
ICCH	V _{CC} = 5.5 V,	VI = 4.5 V		7.3	12		7.3	12	mA
ICCL	V _{CC} = 5.5 V,	$V_{I} = 0$		16.5	26.6		16.5	26.6	mA

[‡] All typical values are at V_{CC} = 5 V, $T_A = 25^{\circ}C$.

§ The output conditions have been chosen to produce a current that closely approximates one half of the true short-circuit output current, IOS.

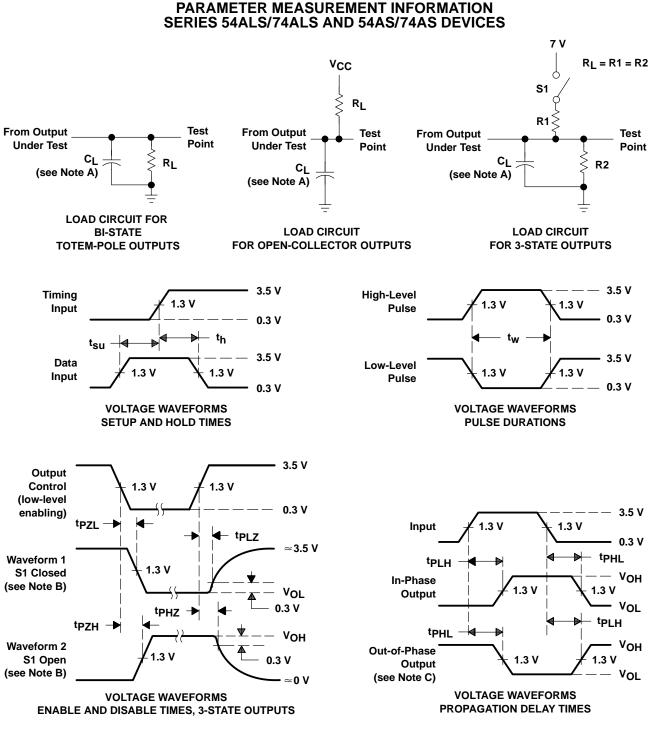
switching characteristics (see Figure 1)

PARAMETER	FROM (INPUT)	то (ОИТРИТ)	CL RL TA	C _L = 50 pF R _L = 500 Ω T _A = MIN to		Ω, to MAX¶		
			SN54	AS32	SN74/	AS32		
			MIN	MAX	MIN	MAX		
^t PLH	A or B	V	1	7.5	1	5.8	ns	
^t PHL	AOIB	I	1	6.5	1	5.8	115	

For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.



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NOTES: A. CL includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
 C. When measuring propagation delay items of 3-state outputs, switch S1 is open.
- D. All input pulses have the following characteristics: PRR \leq 1 MHz, t_r = t_f = 2 ns, duty cycle = 50%.
- E. The outputs are measured one at a time with one transition per measurement.

Figure 1. Load Circuits and Voltage Waveforms



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